MILITARY SPECIFICATION

MICROCIRCUITS, DIGITAL, DTL, NAND GATES, MONOLITHIC SILICON

This amendment forms a part of Military Specification MIL-M-38510/30A, dated 27 December 1974, and is approved for use by all Departments and Agencies of the Department of Defense.

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- 1.2: Delete example of part number in its entirety.
- 1.2.3, Case outline letter B: Delete "1/8" and substitute "3/16".

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- After 3.7(a), add the following new paragraph:
 - "3.8 Microcircuit group assignment. The devices covered by this specification shall be in microcircuit group number 22 (see MIL-M-38510, appendix E)."
- TABLE II, first column, fourth test requirement: Delete "Group C" and substitute "Groups C and D".
- 4.2: In second sentence, delete "groups A, B, and C" and substitute "groups A, B, C, and D"; and delete third sentence in its entirety.
- 4.3(a) and 4.3(b): Delete in their entirety.

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- 4.3(c), 4.3(e), and 4.3(g): Delete in their entirety.
- 4.4.1, first sentence: Delete "consist of the test subgroups and LTPD values shown in" and substitute "be in accordance with".
- 4.4.2 and 4.4.2(a), delete and substitute:
 - "4.4.2 Group B inspection. Group B inspection shall be in accordance with table II of Method 5005 of MIL-STD-883."
- 4.4.3, delete and substitute:
 - "4.4.3 Groups C and D inspections. Groups C and D inspections shall be in accordance with tables III and IV of Method 5005 of MIL-STD-883 and as follows:".
- 4.4.3(b), line 1: Delete "Subgroups 7 and 8" and substitute "Subgroups 3 and 4".
- 4.4.3(c), 4.4.3(d), and 4.4.3(f): Delete in their entirety.

Custodians: Army - EL Navy - EC Air Force - 17

Agent: DSA - ES

Review activities: Army - MI

(Project 5962-0140)

Preparing activity:

Air Force - 17

Air Force - 11, 99 DSA - ES

User activities:

Army - WC, MU Navy - OS, AS, SH, OG

Air Force - 19

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